



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Examiner: Johnston, Phillip A.

David L. Adler, et al.

Serial No. 10/017,262

Art Unit: 2881

Filing Date: 12/14/2001

Attorney Docket No.: P960 (11.700)

Title: Photoelectron Emission Microscope for Wafer and Reticle Inspection

Commissioner of Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

RESPONSE TO FINAL OFFICE ACTION

Sir:

This is responsive to the office action mailed on May 4, 2004. Note that this response is being filed within two months of the mailing date of the final action.